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On the thermal buckling analysis of functionally graded plates with
internal defects using extended isogeometric analysis

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Highlight

- New results of critical thermal buckling temperature rise of FGPs with internal defects are presented.
- An effective and accurate thermal buckling XIGA/level sets using FSDT for FGPs with internal defects is developed.
- New approach eliminates the need for trimmed NURBS surface to describe cutouts.
- The defects have a significant impact on the critical thermal buckling temperature.

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